

Fast extended test access via JTAG and FPGAs

Devadze, Sergei; Jutman, Artur; Aleksejev, Igor; Ubar, Raimund-Johannes International Test Conference 2009 : November 1 - November 6, 2009, Austin Convention Center, Austin, Texas USA : proceedings 2009 / p. 1-7 : ill
<http://dx.doi.org/10.1109/TEST.2009.5355668>

FPGA-based synthetic instrumentation for board test

Aleksejev, Igor; Jutman, Artur; Devadze, Sergei; Odintsov, Sergei; Wenzel, Thomas Proceedings : International Test Conference 2012 2012 / p. 1-10 : ill <https://ieeexplore.ieee.org/document/6401571>